IN THE CLAIMS:

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## Please add new claims 30-37 as follows.

30. (new) Method enabling a command to switch a measure mode to be entered in a dimensional-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by means of deliberate handling operations of a height-command crank.

- 31. (new) Method according to claim 30, wherein said command to switch the measure mode enables said dimension-measuring column to pass into a mode to search for a turn-back point of said piece to be measured.
  - 32. (new) Method according to claim 30, wherein said command to switch the measure mode results in modifying the measuring accuracy and/or resolution.
  - 33. (new) The method according to claim 30, wherein a status of the display of said dimension-measuring column is modified following said command to switch the measure mode so as to indicated the status of a pressing force of said probe tip against a piece to be measured.
  - 34. (new) The method of claim 30, wherein said command to switch the measure mode is entered by pressing said probe tip against a piece to be measured during a time interval shorter than a predetermined value.

35. (new) Dimension-measuring column, comprising:
a probe tip designed for being brought into contact with
a piece to be measured,
a height-command crank for displacing said probe tip,
a measuring and displaying system that allows the
position of said probe tip to be determined and displayed,
wherein a command to switch the measure mode is entered
by means of deliberate handling operations of the
height-command crank.

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36. (new) The dimension-measuring column of claim 35, wherein said command to switch the measure mode enables a measuring column to pass into a mode to search for a turn-back point of said piece to be measured.

37. (new) The dimension-measuring column of claim 35, wherein said mode switch command results in modifying the measuring accuracy and/or resolution.